


Search Notes 	Application/Control No. 10575165	Applicant(s)/Patent Under Reexamination VION, PATRICK
	Examiner Christopher S Kim	Art Unit 3752

SEARCHED			
Class	Subclass	Date	Examiner
239	504, 499, 427, 370, 590.3, 590.5	4/12/08	CK

SEARCH NOTES		
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INTERFERENCE SEARCH			
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